# International Rectifier

- Logic-Level Gate Drive
- Advanced Process Technology
- Surface Mount (IRLZ44NS)
- Low-profile through-hole (IRLZ44NL)
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- Lead-Free

#### Description

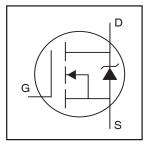
Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

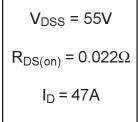
The  $D^2Pak$  is a surface mount power package capable of accommodating die sizes up to HEX-4. It provides the highest power capability and the lowest possible onresistance in any existing surface mount package. The  $D^2Pak$  is suitable for high current applications because of its low internal connection resistance and can dissipate up to 2.0W in a typical surface mount application.

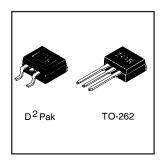
The through-hole version (IRLZ44NL) is available for low-profile applications.

## IRLZ44NS/LPbF

**HEXFET® Power MOSFET** 







#### **Absolute Maximum Ratings**

	Parameter	Max.	Units	
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V®	47		
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V®	33	A	
I <sub>DM</sub>	Pulsed Drain Current ① ⑤	160		
P <sub>D</sub> @T <sub>A</sub> = 25°C	Power Dissipation	3.8	W	
P <sub>D</sub> @T <sub>C</sub> = 25°C	Power Dissipation	110	W	
	Linear Derating Factor	0.71	W/°C	
V <sub>GS</sub>	Gate-to-Source Voltage	±16	V	
E <sub>AS</sub>	Single Pulse Avalanche Energy@®	210	mJ	
I <sub>AR</sub>	Avalanche Current①	25	Α	
E <sub>AR</sub>	Repetitive Avalanche Energy①	11	mJ	
dv/dt	Peak Diode Recovery dv/dt 3 5	5.0	V/ns	
TJ	Operating Junction and	-55 to + 175		
T <sub>STG</sub>	Storage Temperature Range		°C	
	Soldering Temperature, for 10 seconds	300 (1.6mm from case )		

#### **Thermal Resistance**

	Parameter	Тур.	Max.	Units
$R_{\theta JC}$	Junction-to-Case		1.4	0000
$R_{\theta JA}$	Junction-to-Ambient ( PCB Mounted,steady-state)**		40	°C/W

#### Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	55			V	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		0.070		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA <sup>⑤</sup>
				0.022		V <sub>GS</sub> = 10V, I <sub>D</sub> = 25A ⊕
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance			0.025	Ω	V <sub>GS</sub> = 5.0V, I <sub>D</sub> = 25A ④
				0.035	] [	V <sub>GS</sub> = 4.0V, I <sub>D</sub> = 21A ④
V <sub>GS(th)</sub>	Gate Threshold Voltage	1.0		2.0	V	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$
g <sub>fs</sub>	Forward Transconductance	21			S	V <sub>DS</sub> = 25V, I <sub>D</sub> = 25A <sup>⑤</sup>
	Duein to Course Leakans Comment			25	μA	V <sub>DS</sub> = 55V, V <sub>GS</sub> = 0V
IDSS	Drain-to-Source Leakage Current			250	μΛ	$V_{DS} = 44V$ , $V_{GS} = 0V$ , $T_{J} = 150$ °C
lasa	Gate-to-Source Forward Leakage			100	nA	V <sub>GS</sub> = 16V
I <sub>GSS</sub>	Gate-to-Source Reverse Leakage			-100	''^	V <sub>GS</sub> = -16V
Qg	Total Gate Charge			48		I <sub>D</sub> = 25A
Q <sub>gs</sub>	Gate-to-Source Charge			8.6	nC	V <sub>DS</sub> = 44V
Q <sub>gd</sub>	Gate-to-Drain ("Miller") Charge			25		$V_{GS}$ = 5.0V, See Fig. 6 and 13 $\oplus$ $\odot$
t <sub>d(on)</sub>	Turn-On Delay Time		11			V <sub>DD</sub> = 28V
t <sub>r</sub>	RiseTime		84		ns	I <sub>D</sub> = 25A
t <sub>d(off)</sub>	Turn-Off Delay Time		26			$R_G = 3.4\Omega, V_{GS} = 5.0V$
t <sub>f</sub>	Fall Time		15			$R_D = 1.1\Omega$ , See Fig. 10 $\oplus$ $\odot$
L <sub>S</sub>	Internal Source Inductance		7.5		11	Between lead,
					nH	and center of die contact
C <sub>iss</sub>	Input Capacitance		1700			V <sub>GS</sub> = 0V
Coss	Output Capacitance		400		pF	$V_{DS} = 25V$
C <sub>rss</sub>	Reverse Transfer Capacitance		150			f = 1.0MHz, See Fig. 5⑤

#### Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions	
ls	Continuous Source Current			47		MOSFET symbol	
	(Body Diode)		-     47	A	showing the		
I <sub>SM</sub>	Pulsed Source Current	Pulsed Source Current (Body Diode) ① 10		400	400	^	integral reverse
	(Body Diode) ①		160		p-n junction diode.		
V <sub>SD</sub>	Diode Forward Voltage			1.3	V	T <sub>J</sub> = 25°C, I <sub>S</sub> = 25A, V <sub>GS</sub> = 0V ④	
t <sub>rr</sub>	Reverse Recovery Time		80	120	ns	T <sub>J</sub> = 25°C, I <sub>F</sub> = 25A	
Q <sub>rr</sub>	Reverse Recovery Charge		210	320	nC	di/dt = 100A/µs ⊕ ⑤	
t <sub>on</sub>	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )					

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. ( See fig. 11 )
- ②  $V_{DD}$  = 25V, starting  $T_J$  = 25°C, L =470 $\mu$ H  $R_G$  = 25 $\Omega$ ,  $I_{AS}$  = 25A. (See Figure 12)
- 4 Pulse width  $\leq 300 \mu s$ ; duty cycle  $\leq 2\%$ .
- ⑤ Uses IRLZ44N data and test conditions

<sup>\*\*</sup> When mounted on 1" square PCB (FR-4 or G-10 Material).
For recommended footprint and soldering techniques refer to application note #AN-994.

## International TOR Rectifier

## IRLZ44NS/LPbF

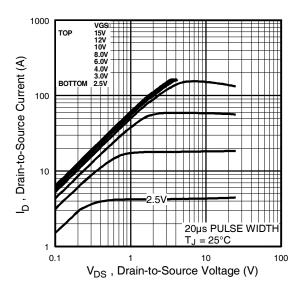
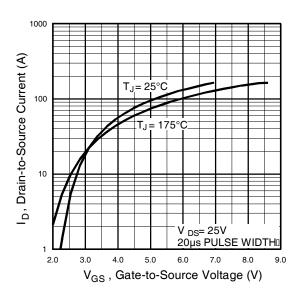


Fig 1. Typical Output Characteristics

Fig 2. Typical Output Characteristics



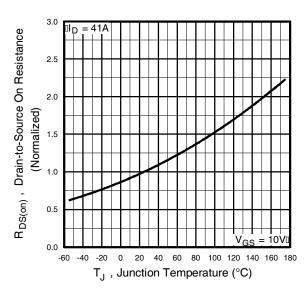


Fig 3. Typical Transfer Characteristics

**Fig 4.** Normalized On-Resistance Vs. Temperature

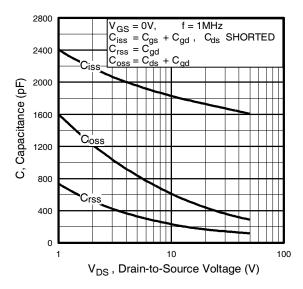
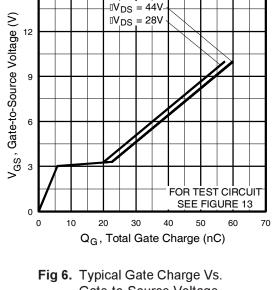


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage



I<sub>D</sub> = 25A

Gate-to-Source Voltage

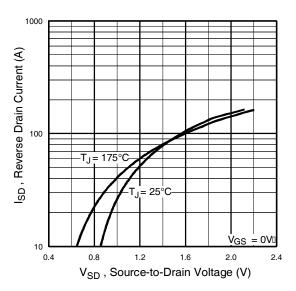


Fig 7. Typical Source-Drain Diode Forward Voltage

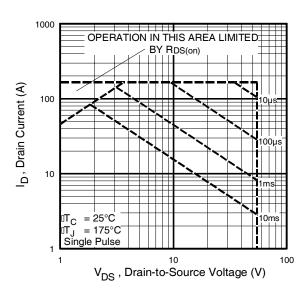


Fig 8. Maximum Safe Operating Area

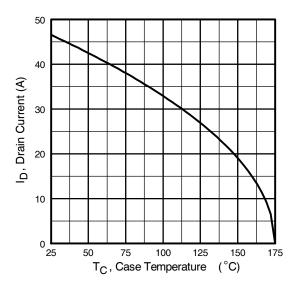


Fig 9. Maximum Drain Current Vs.
Case Temperature

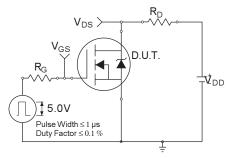


Fig 10a. Switching Time Test Circuit

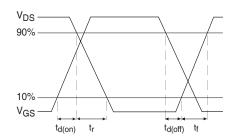


Fig 10b. Switching Time Waveforms

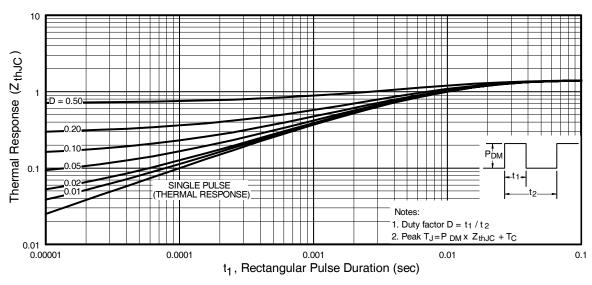


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

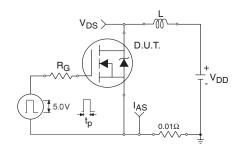


Fig 12a. Unclamped Inductive Test Circuit

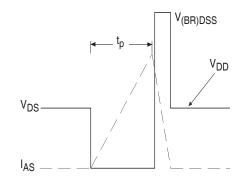


Fig 12b. Unclamped Inductive Waveforms

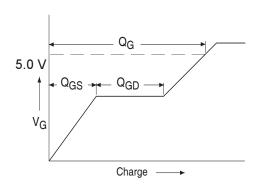
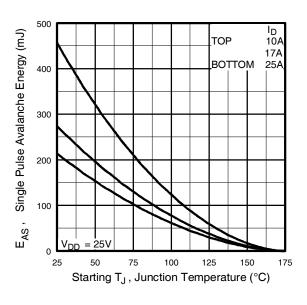


Fig 13a. Basic Gate Charge Waveform



**Fig 12c.** Maximum Avalanche Energy Vs. Drain Current

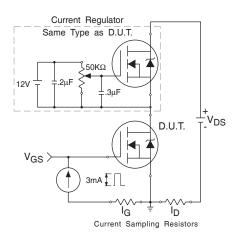
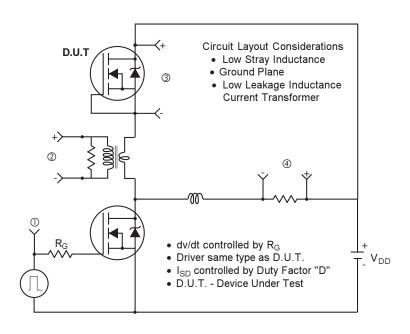
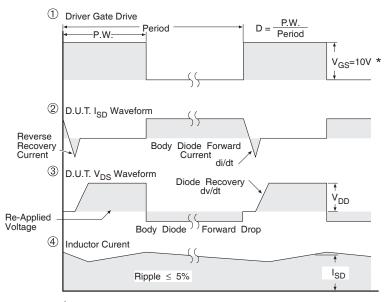


Fig 13b. Gate Charge Test Circuit

#### Peak Diode Recovery dv/dt Test Circuit

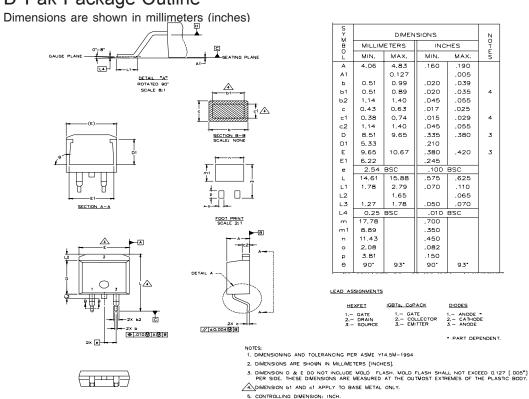




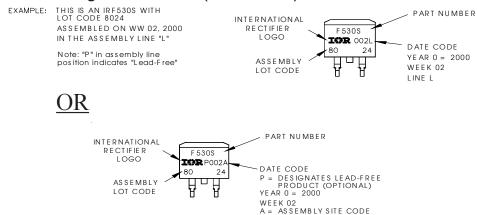
\*  $V_{GS}$  = 5V for Logic Level Devices

Fig 14. For N-Channel HEXFETS

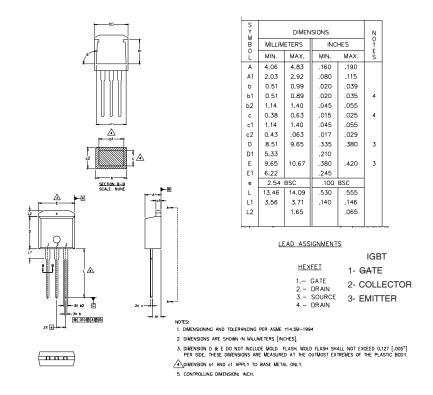
#### D<sup>2</sup>Pak Package Outline



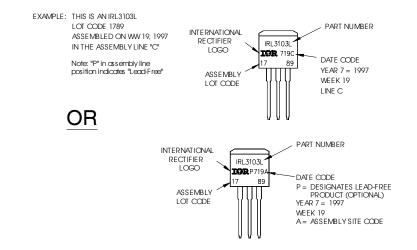
## D<sup>2</sup>Pak Part Marking Information (Lead-Free)



#### TO-262 Package Outline

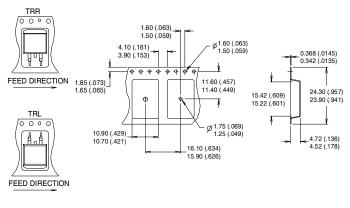


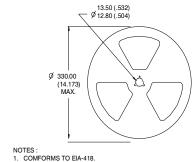
#### TO-262 Part Marking Information

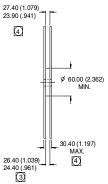


#### D<sup>2</sup>Pak Tape & Reel Infomation

Dimensions are shown in millimeters (inches)







- COMFORMS TO EIA-418.
  CONTROLLING DIMENSION: MILLIMETER.
  DIMENSION MEASURED @ HUB.
  INCLUDES FLANGE DISTORTION @ OUTER EDGE.

Data and specifications subject to change without notice.

International

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Note: For the most current drawings please refer to the IR website at: <a href="http://www.irf.com/package/">http://www.irf.com/package/</a>

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